Case No. IPR2016-01378¹ Patent Number 6,197,696

Before JUSTIN T. ARBES, MICHAEL J. FITZPATRICK, and JENNIFER MEYER CHAGNON, *Administrative Patent Judges*.

PATENT OWNER'S UPDATED LIST OF EXHIBITS

¹ GlobalFoundries U.S. Inc., who filed Petition IPR2017-00923, has been joined as a petitioner in this proceeding.



In accordance with 37 C.F.R. § 42.63(e), Patent Owner Godo Kaisha IP Bridge 1 ("Patent Owner") hereby submits a current listing of Patent Owner's exhibits.

List of Exhibits

Exhibit	Description	Previously Filed
EX2001	N. Sclater & J. Markus, McGraw-Hill Electronics	X
	Dictionary (6th ed. 1997) (excerpted)	
EX2002	R. F. Graf, Modern Dictionary of Electronics (6th ed. 1984) (excerpted)	X
EX2003	R. F. Graf, Modern Dictionary of Electronics (7th ed.	X
	1999) (excerpted)	
EX2004	S. M. Kaplan, Wiley Electrical and Electronics	X
	Engineering Dictionary (2004) (excerpted)	
EX2005	October 7, 2016 Preliminary Constructions, <i>Godo</i>	X
	Kaisha IP Bridge 1 v. Broadcom Ltd., et al., (E.D. Tex 2:16-CV-134-JRG-RSP)	
EX2006	Hans Domininghaus, Plastics for Engineers: Materials,	X
	Properties, Applications (1993) (excerpted)	
EX2007	U. S. Patent No. 6,147,009 to Grill et al.	X
EX2008	Declaration of Seung Woo Hur	X
EX2009	Declaration of Alexander Glew, Ph.D. In Support of	X
	Patent Owner's Response Under 37 C.F. R. § 42.120	
EX2010	Deposition of Bruce Smith in Taiwan Semiconductor	X
	Manufacturing Co., v. Godo Kaisha IP Bridge	
	1(P.T.A.B. IPR2016-01376) taken on March 23, 2017	
EX2011	Redline Comparing Grill (EX1005) with Grill's	X
	Provisional (EX1017) Application	
EX2012	Japanese Patent Application 10-079371 to Aoi as	X
	Submitted in European Patent Application No. 99 105	
	946.0 with accompanying translation	
EX2013	Declaration of Takeo Ohashi, Ph.D. In Support of	X
	Patent Owner's Response Under 37 C.F. R. § 42.120	
EX2014	Influence of reactor wall conditions on etch processes	X
	in inductively coupled fluorocarbon plasmas by M.	



	Schaepkens, et al., J. Vac. Sci. Tech. A 16(4), Jul/Aug 1998	
EX2015	Handbook of VLSI Microlithography, Second Edition, Principles, Technology, and Applications, edited by John N. Helbert, Noyes Publications, William Andrew Publishing, LLC, 2001	X
EX2016	Silicon VLSI Technology Fundamentals, Practice and Modeling, by James D. Plummer, et al., Prentice Hall, 2000	X
EX2017	Microlithography: Science and Technology, by James R. Sheats and Bruce W. Smith, Marcel Dekker, Inc., 1998	Х
EX2018	<i>Microlithography: Science and Technology</i> , 2 nd ed., by James R. Sheats and Bruce W. Smith, CRC Press, 2007	X
EX2019	<i>Microlithography: Science and Technology</i> , 2 nd ed., by James R. Sheats and Bruce W. Smith, CRC Press, 2007	X
EX2020	Silicon Processing for The VLSI Era Vol. 2 Process Integration by Stanley Wolf and R.N. Tauber, Lattice Press, 1986	Х
EX2021	Kenkyusha's New Japanese-English Dictionary, 4 th ed., 35 th Impression, published by Kenkyusha Ltd., 1997	X
EX2022	Declaration of Jordan M. Rossen In Support of Patent Owner's Response Under 37 C.F. R. § 42.120	X
EX2023	Declaration of Susann Brailey and Exhibit A regarding Influence of reactor wall conditions on etch processes in inductively coupled fluorocarbon plasmas by M. Schaepkens, et al., J. Vac. Sci. Tech. A 16(4), Jul/Aug 1998	Served only.
EX2024	Affidavit of Pamela Stansbury regarding <i>Influence of</i> reactor wall conditions on etch processes in inductively coupled fluorocarbon plasmas by M. Schaepkens, et al., J. Vac. Sci. Tech. A 16(4), Jul/Aug 1998	Served only.
EX2025	Influence of reactor wall conditions on etch processes in inductively coupled fluorocarbon plasmas by M. Schaepkens, et al., J. Vac. Sci. Tech. A 16(4), Jul/Aug 1998	Served only.
EX2026	Library of Congress Certification of <i>Handbook of VLSI Microlithography, Second Edition, Principles, Technology, and Applications</i> , edited by John N.	Served only.



	1	
	Helbert, Noyes Publications, William Andrew	
	Publishing, LLC, 2001 (excerpted)	
EX2027	Library of Congress Certification of <i>Handbook of VLSI</i>	X
	Microlithography, Principles, Technology, and	
	Applications, edited by William B. Glendinning and	
	John N. Helbert, Noyes Publications, William Andrew	
	Publishing, LLC, 1991 (excerpted)	
EX2028	Library of Congress Certification of Silicon VLSI	Served
	Technology Fundamentals, Practice and Modeling, by	only.
	James D. Plummer, et al., Prentice Hall, 2000	
	(excerpted)	
EX2029	Affidavit of Pamela Stansbury regarding Silicon VLSI	Served
	Technology Fundamentals, Practice and Modeling, by	only.
	James D. Plummer, et al., Prentice Hall, 2000	
EX2030	Silicon VLSI Technology Fundamentals, Practice and	Served
	Modeling, by James D. Plummer, et al., Prentice Hall,	only.
	2000 (excerpted)	
EX2031	Library of Congress Certification of <i>Microlithography:</i>	Served
	Science and Technology, by James R. Sheats and Bruce	only.
	W. Smith, Marcel Dekker, Inc., 1998 (excerpted)	
EX2032	Library of Congress Certification of <i>Microlithography:</i>	Served
	Science and Technology, 2 nd ed., by Kazuaki Suzuki and	only.
	Bruce W. Smith, CRC Press, 2007 (Chapter 12)	
	(excerpted) (Smith Deposition Exhibit 3)	
EX2033	Library of Congress Certification of <i>Microlithography:</i>	Served
	Science and Technology, 2 nd ed., by Kazuaki Suzuki and	only.
	Bruce W. Smith, CRC Press, 2007 (Chapter 11)	•
	(excerpted) (Smith Deposition Exhibit 9)	
EX2034	Affidavit of Pamela Stansbury regarding Silicon	Served
	Processing for The VLSI Era Vol. 1 Process Technology	only.
	by Stanley Wolf and R.N. Tauber, Lattice Press, 1986	•
EX2035	Silicon Processing for The VLSI Era Vol. 1 Process	Served
	Technology by Stanley Wolf and R.N. Tauber, Lattice	only.
	Press, 1986 (excerpted)	•
EX2036	U.S. Pat. No. 5,322,749	Served
		only.
EX2037	U.S. Pat. No. 6,181,420	Served
		only.
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EX2038	U.S. Pat. No. 6,808,647	Served
		only.
EX2039	Declaration of Jordan M. Rossen	Served
		only.
EX2040	Transcript of the Deposition of Dr. B. Smith	X
	(August 2, 2017)	
EX2041	Patent Owner's Demonstrative Slides	



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